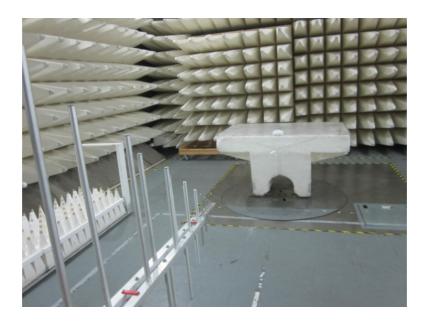
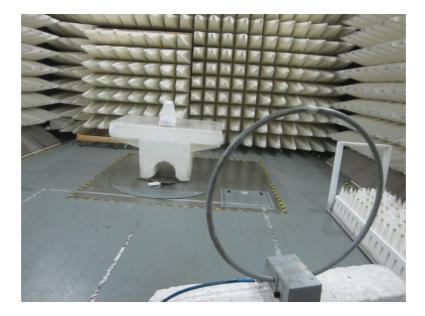


Photograph No.1 Setup for carrier field strength measurements for EUT in X-axis position

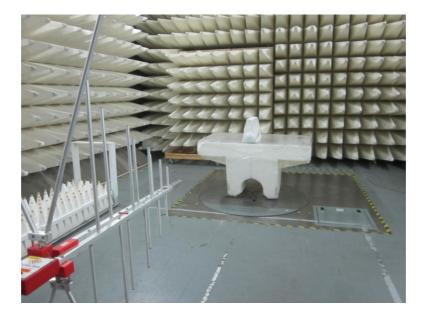


Photograph No.2 Setup for carrier field strength measurements for EUT in Y-axis position

Photograph No.3 Setup for spurious emission field strength measurements in the anechoic chamber below 30 MHz



# Photograph No.4 Setup for spurious emission field strength measurements in the anechoic chamber in 30 – 1000 MHz range



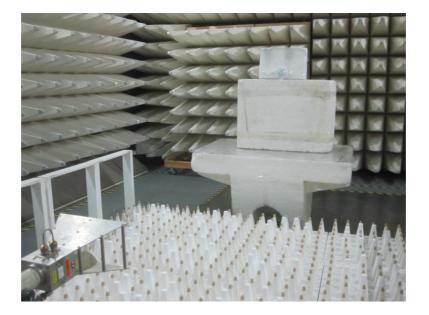
### Photograph No.5 Setup for carrier field strength, spurious emission field strength measurements in the anechoic chamber below 1000 MHz, EUT close view in X-axis position



#### Photograph No.6 Setup for carrier field strength measurements in the anechoic chamber, EUT close view in Y-axis position



# Photograph No.7 Setup for spurious emission field strength measurements in the anechoic chamber above 1000 MHz range



# Photograph No.8 Setup for hopping parameters and band edge emissions measurements



